

Search Notes**Application/Control No.**

10/090,939

Examiner

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Applicant(s)/Patent under Reexamination

TAZAWA ET AL.

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	223	12/12/2005	BQN
370	395.1	12/12/2005	BQN
370	474	12/12/2005	BQN
370	352	12/12/2005	BQN
370	241	12/12/2005	BQN
709	238	12/12/2005	BQN
709	227	12/12/2005	BQN
709	247	12/12/2005	BQN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	12/12/2005	BQN
Consulted with Andrew Lee	12/12/2005	BQN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner